

L Number	Hits	Search Text	DB	Time stamp
1	1702	((JTAG adj3 test\$3) or ("IEEE 1149.1") or (boundary adj2 scan adj2 test\$3))	USPAT; EPO; JPO; DERWENT	2003/07/25 15:46
2	5	(plurality or several or multiple) adj2 (chip\$1 or IC\$1) near5 (integral\$3 adj2 seal\$2)	USPAT; EPO; JPO; DERWENT	2003/07/25 15:48
3	7	(plurality or several or multiple) adj2 (chip\$1 or IC\$1) same (integral\$3 adj2 seal\$2)	USPAT; EPO; JPO; DERWENT	2003/07/25 15:49
4	(29)	(plurality or several or multiple) adj2 (chip\$1 or IC\$1) and (integral\$3 adj2 seal\$2)	USPAT; EPO; JPO; DERWENT	2003/07/25 15:49
5	0	(plurality or several or multiple) adj2 (chip\$1 or IC\$1) and (integral\$3 adj2 seal\$2) and (air adj1 tight)	USPAT; EPO; JPO; DERWENT	2003/07/25 15:49
6	17	(integral\$3 adj2 seal\$2) same (air adj1 tight)	USPAT; EPO; JPO; DERWENT	2003/07/25 15:49
7	100	(integral\$3 adj2 seal\$2) and (air adj1 tight)	USPAT; EPO; JPO; DERWENT	2003/07/25 15:50
8	0	(integral\$3 adj2 seal\$2) and (air adj1 tight) and (((JTAG adj3 test\$3) or ("IEEE 1149.1") or (boundary adj2 scan adj2 test\$3)))	USPAT; EPO; JPO; DERWENT	2003/07/25 15:50
9	(27)	(integral\$3 adj2 seal\$2) and (air adj1 tight) and test\$3	USPAT; EPO; JPO; DERWENT	2003/07/25 15:51
10	0	(integral\$3 adj2 seal\$2) and (air adj1 tight) and (IC near3 test\$3)	USPAT; EPO; JPO; DERWENT	2003/07/25 15:51
11	15576	integral\$3 adj2 seal\$2) (IC near3 test\$3	USPAT; EPO; JPO; DERWENT	2003/07/25 15:52
12	(35)	(air adj1 tight) and (IC near4 test\$3)	USPAT; EPO; JPO; DERWENT	2003/07/25 15:52
13	(3)	integral\$3 adj2 seal\$2) and (IC near3 test\$3	USPAT; EPO; JPO; DERWENT	2003/07/25 15:52